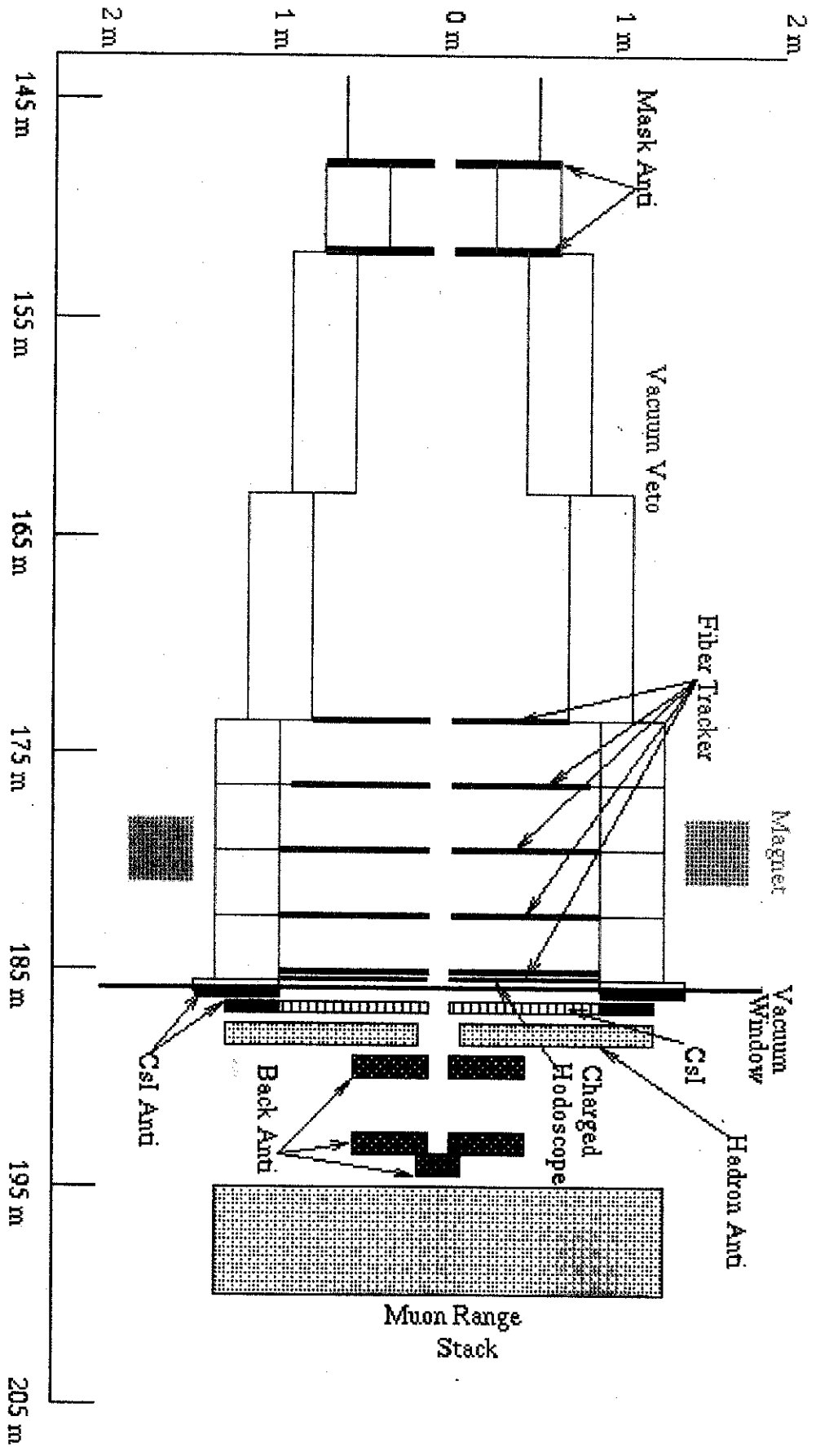


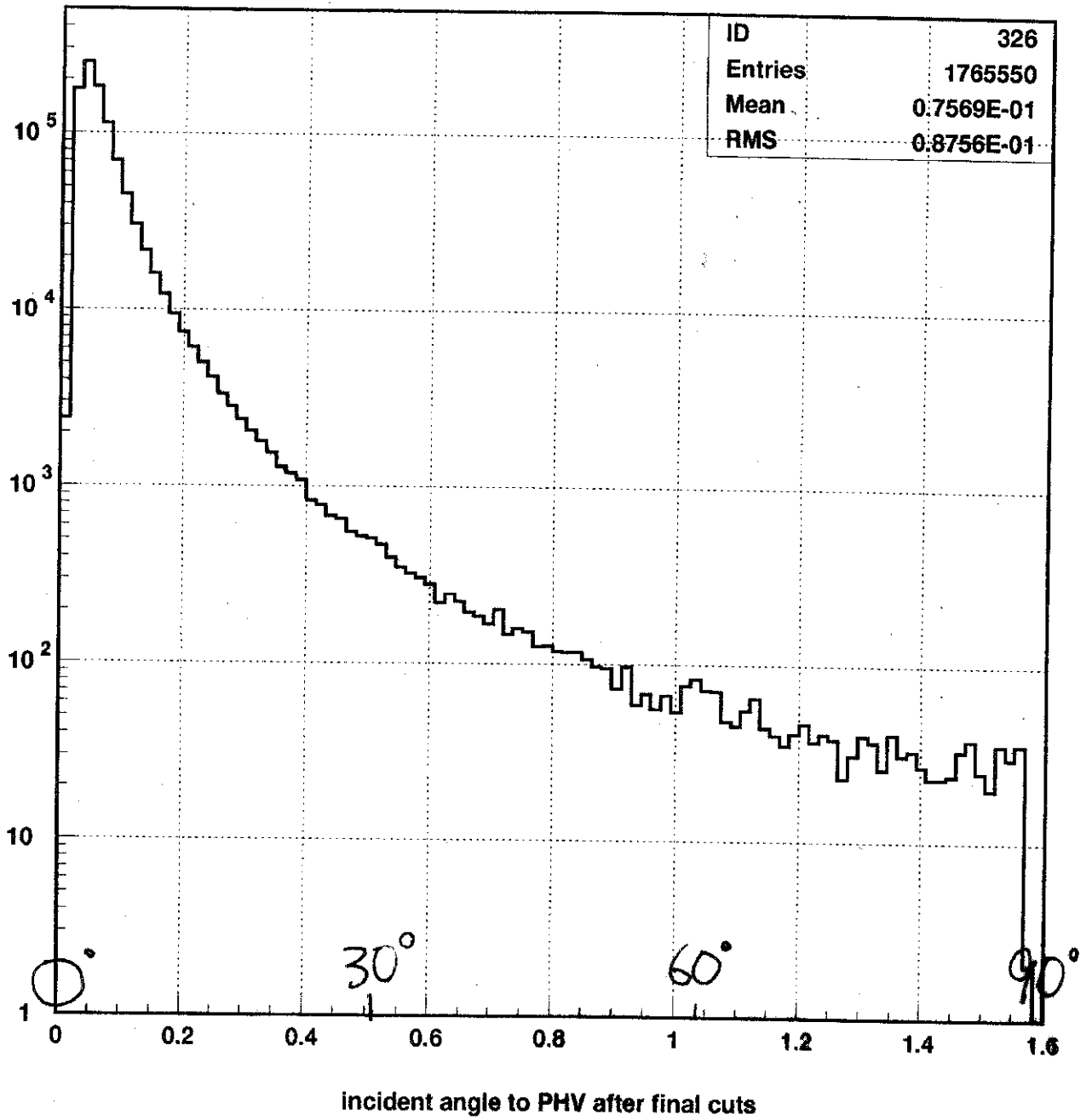
A study of the photon veto
inefficiency dependence on
incident angle

Ken Sakashita
(Osaka University)

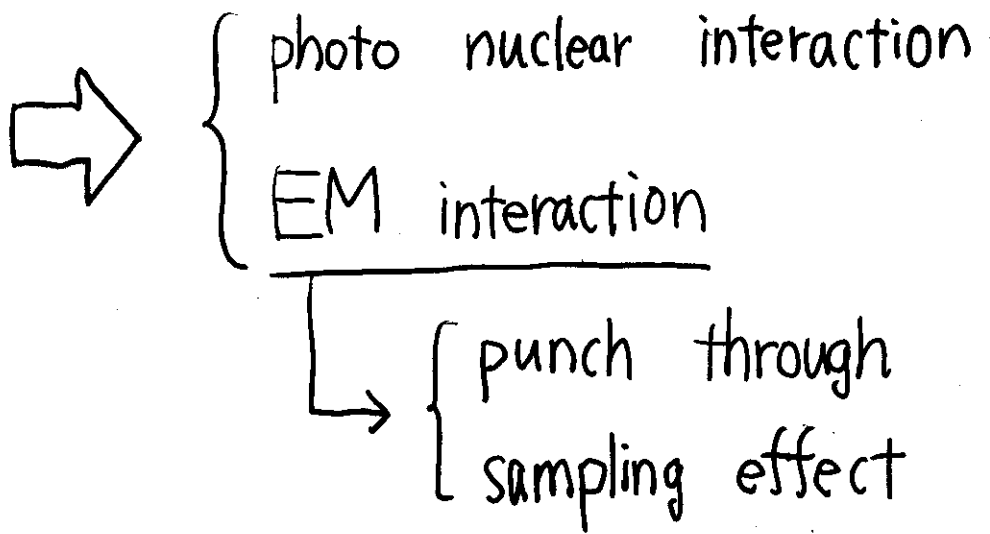
KAMI DETECTOR LAYOUT



$K_L \rightarrow \pi^0 \pi^0$



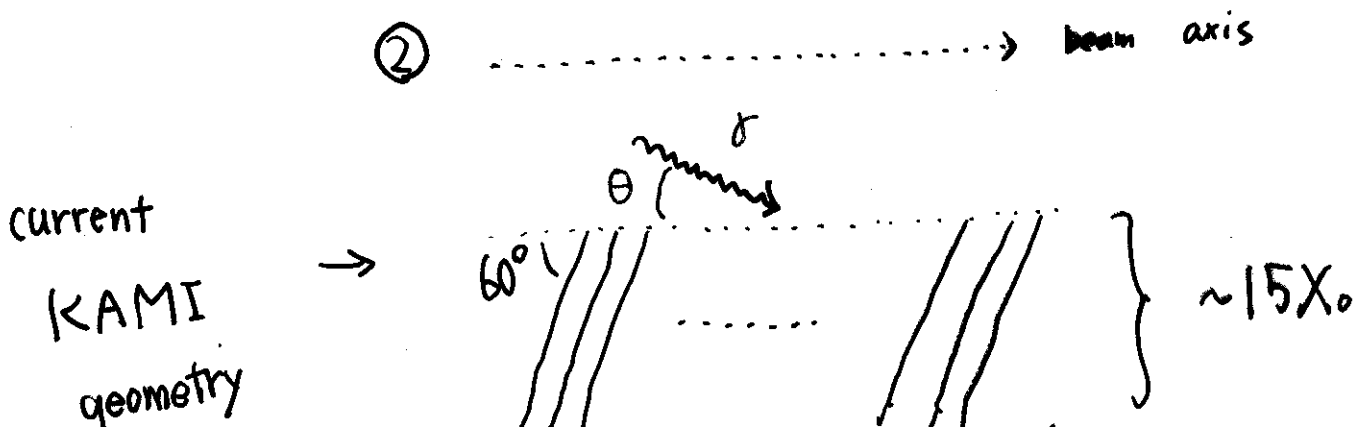
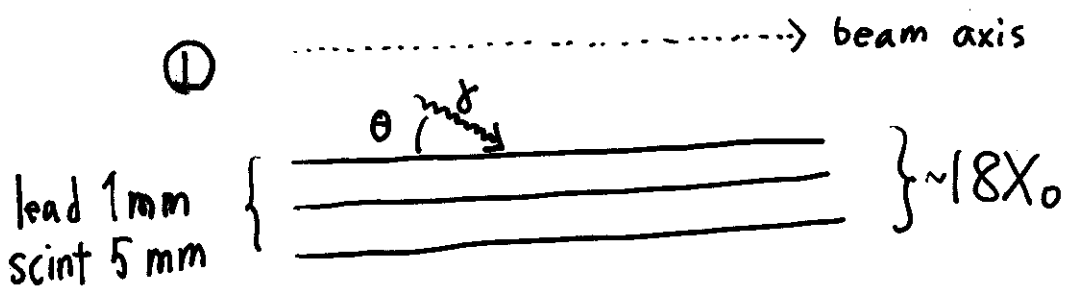
The photon veto inefficiency

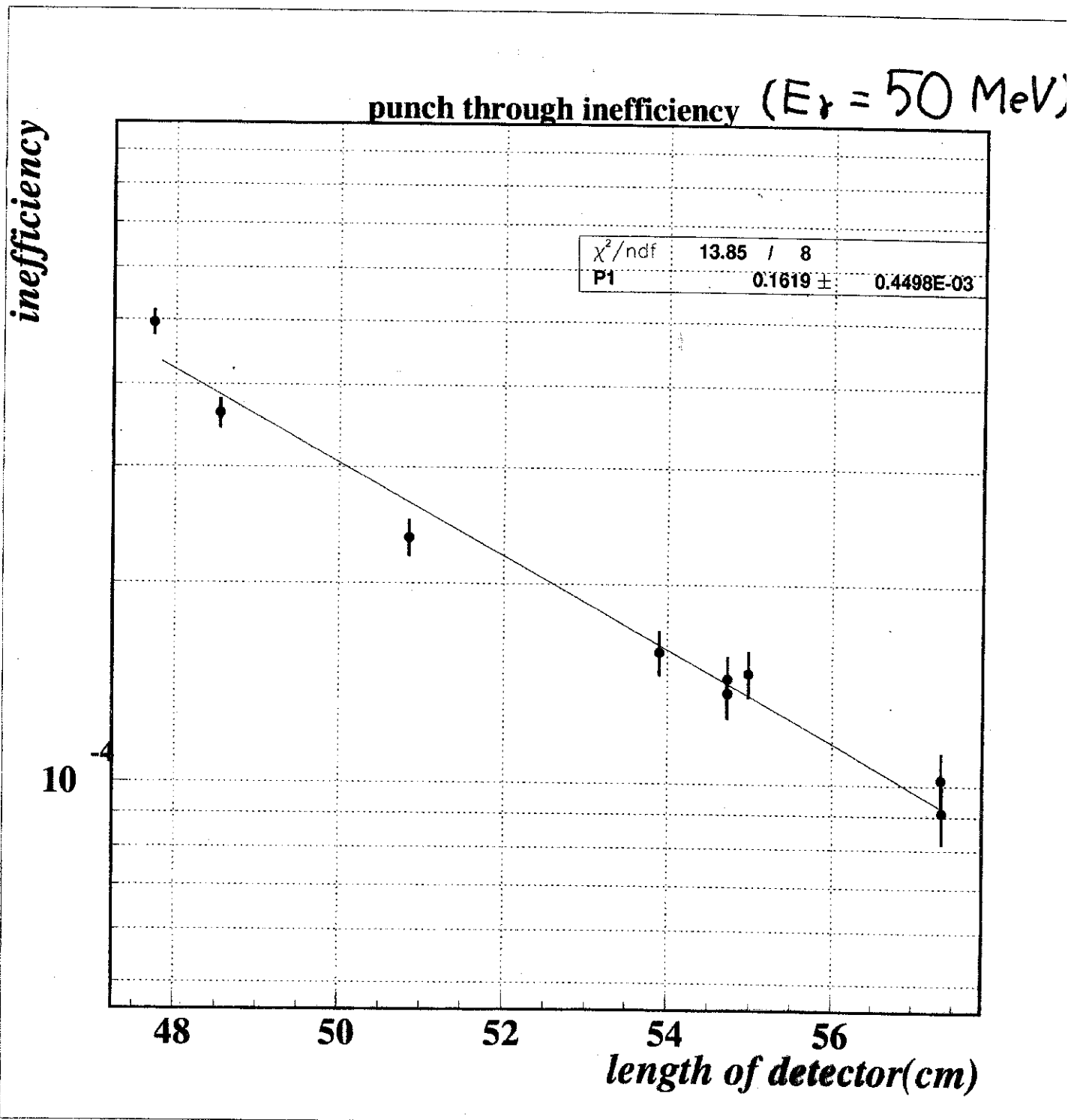


I studied the photo veto inefficiency
caused by EM interaction. (using EGS4)

• $E_\gamma = 50 \text{ MeV}$

• detector's geometry : 2 type

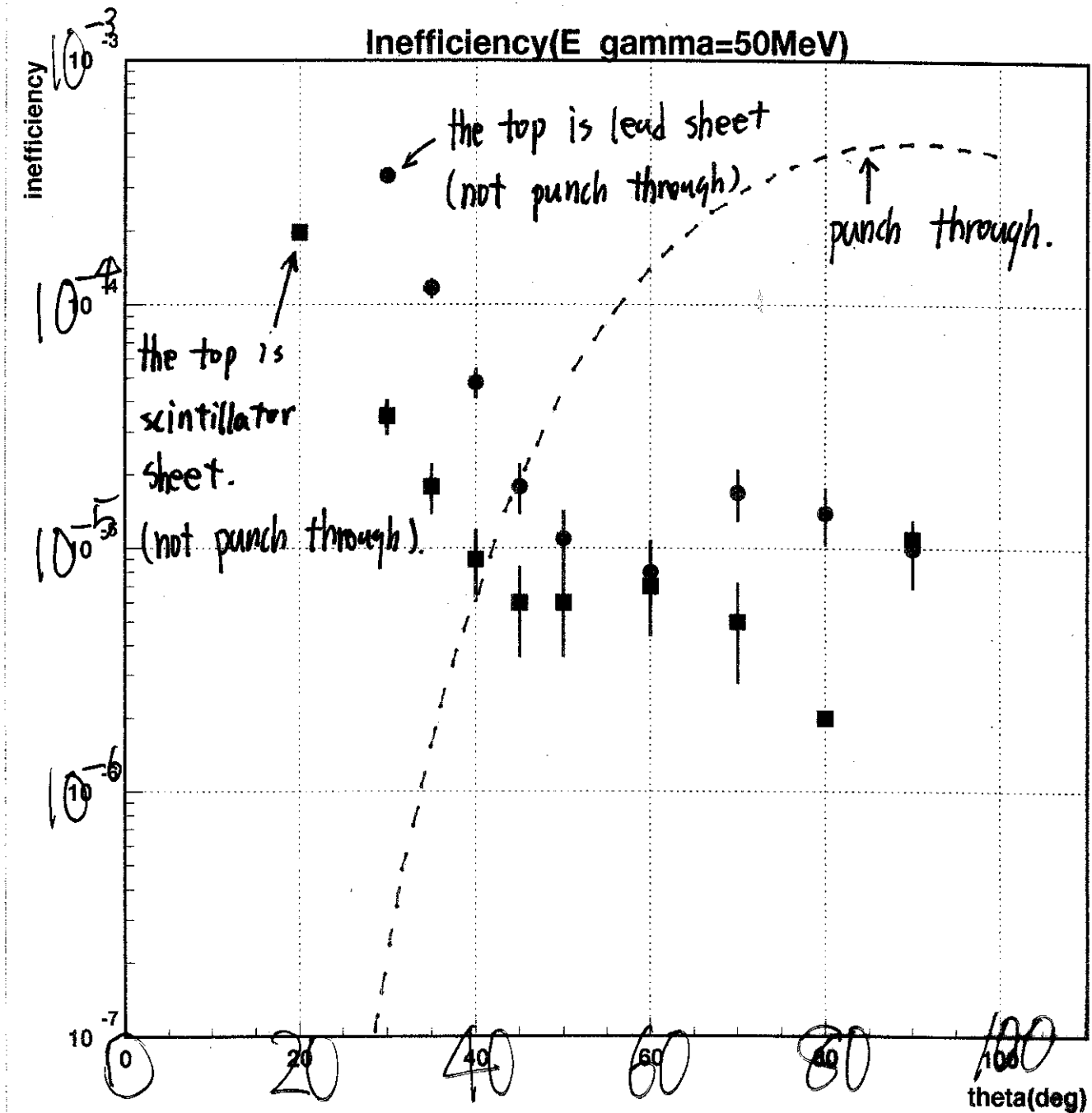
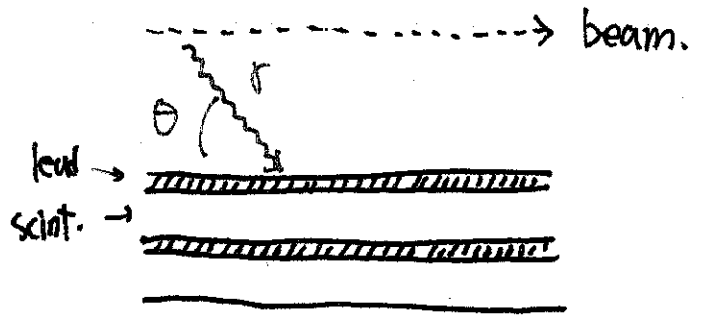




punch through

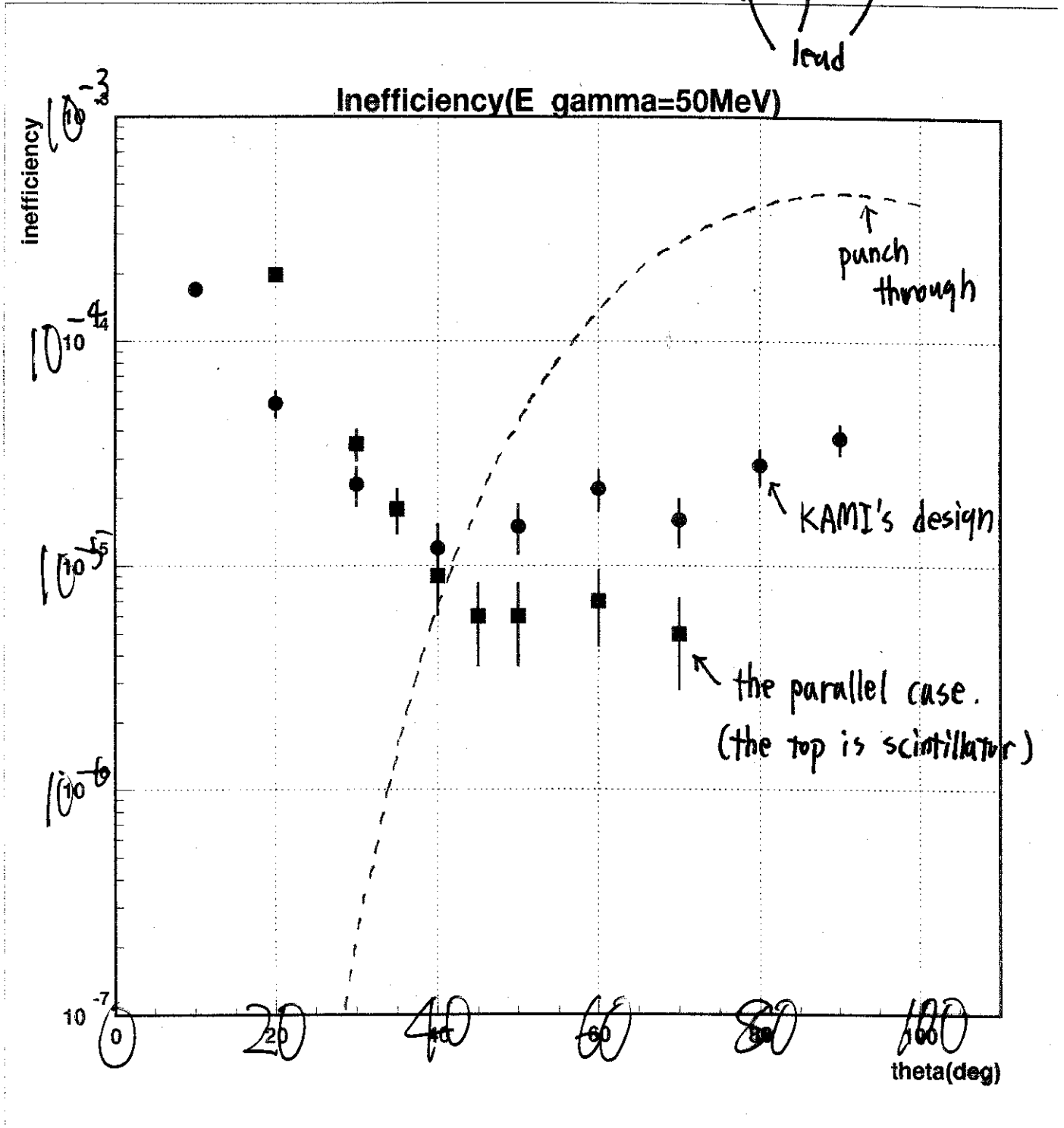
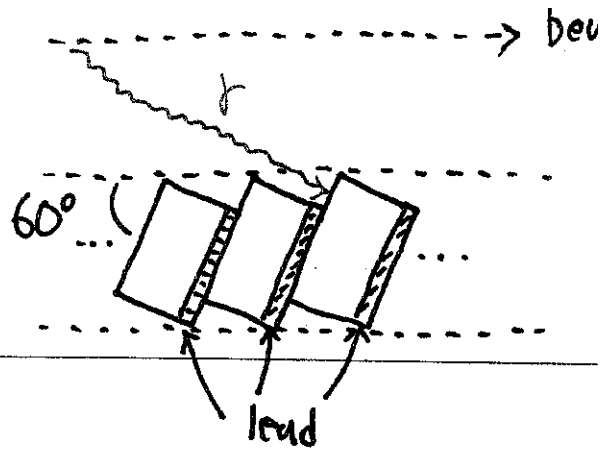
\Rightarrow (inefficiency) = $e^{-0.169 \times x}$

First, I studied one case.
 The geometry of detector is parallel to the beam axis.

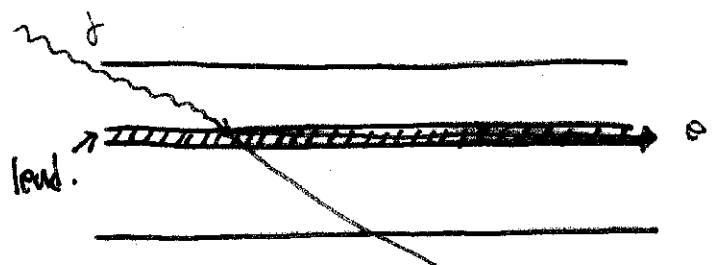


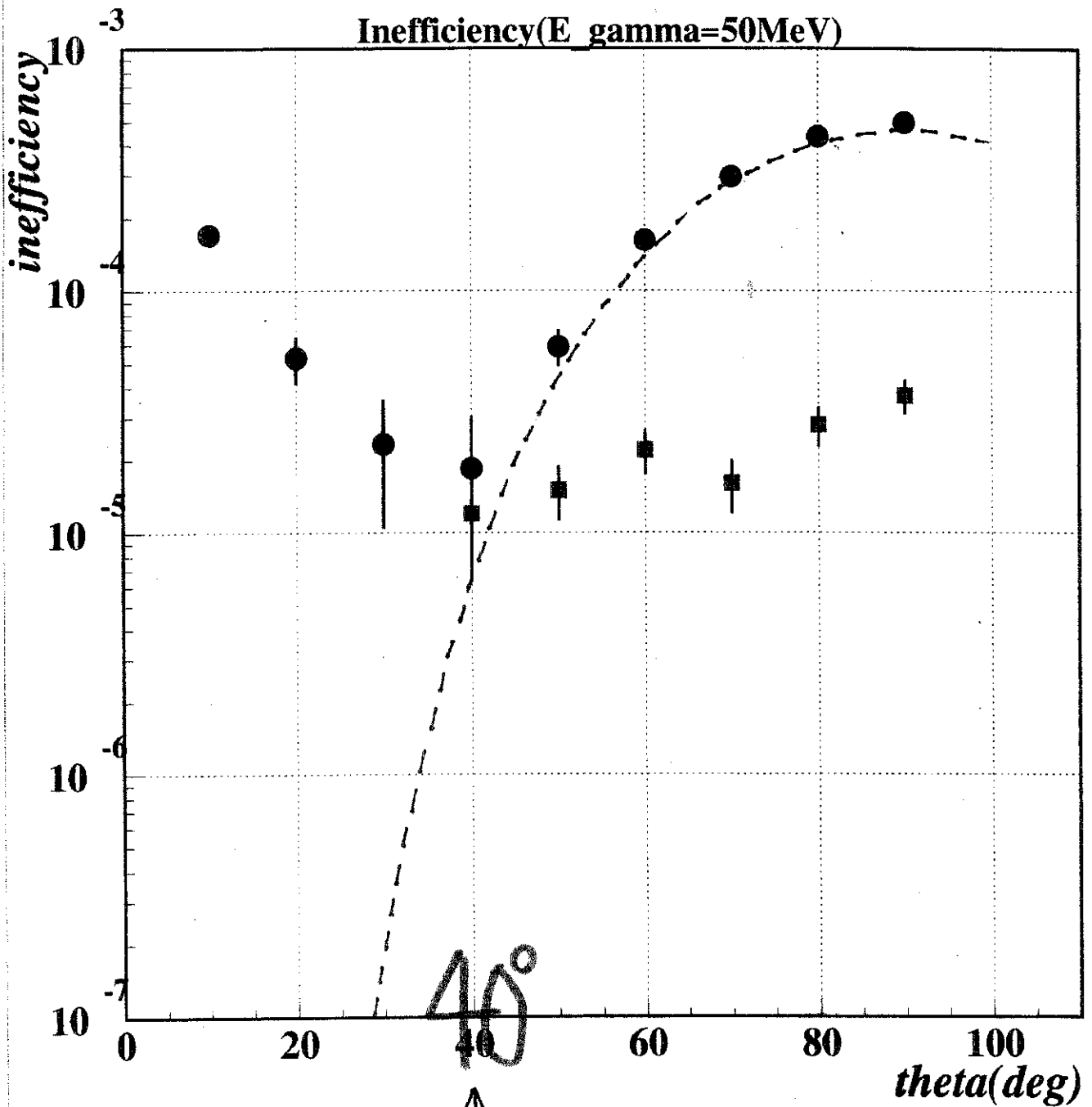
In the case that the top sheet is scintillator, the backplash is detected by the top scintillator. So, the inefficiency is better than the case that the top sheet is lead.

Next, I studied the case that the detector's geometry is current KAMI's design.

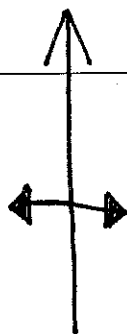


In the parallel case, when the photon's incident angle is small, the electron go to through the length in the lead sheet.





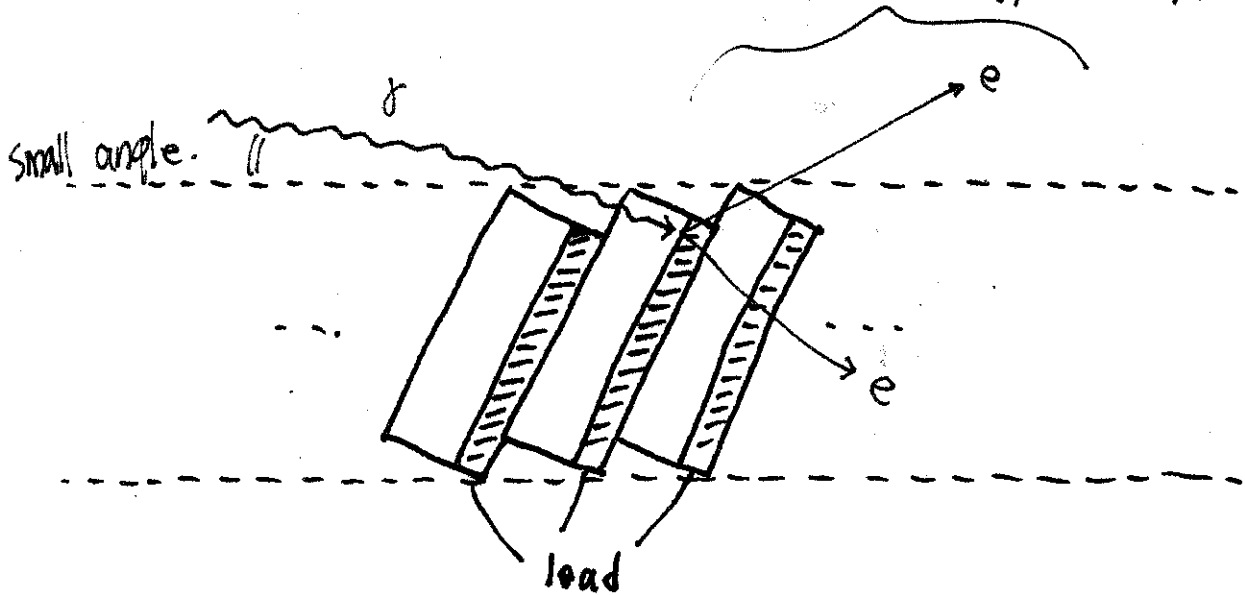
"not punch through"
is dominate.



"punch through"
is dominate.

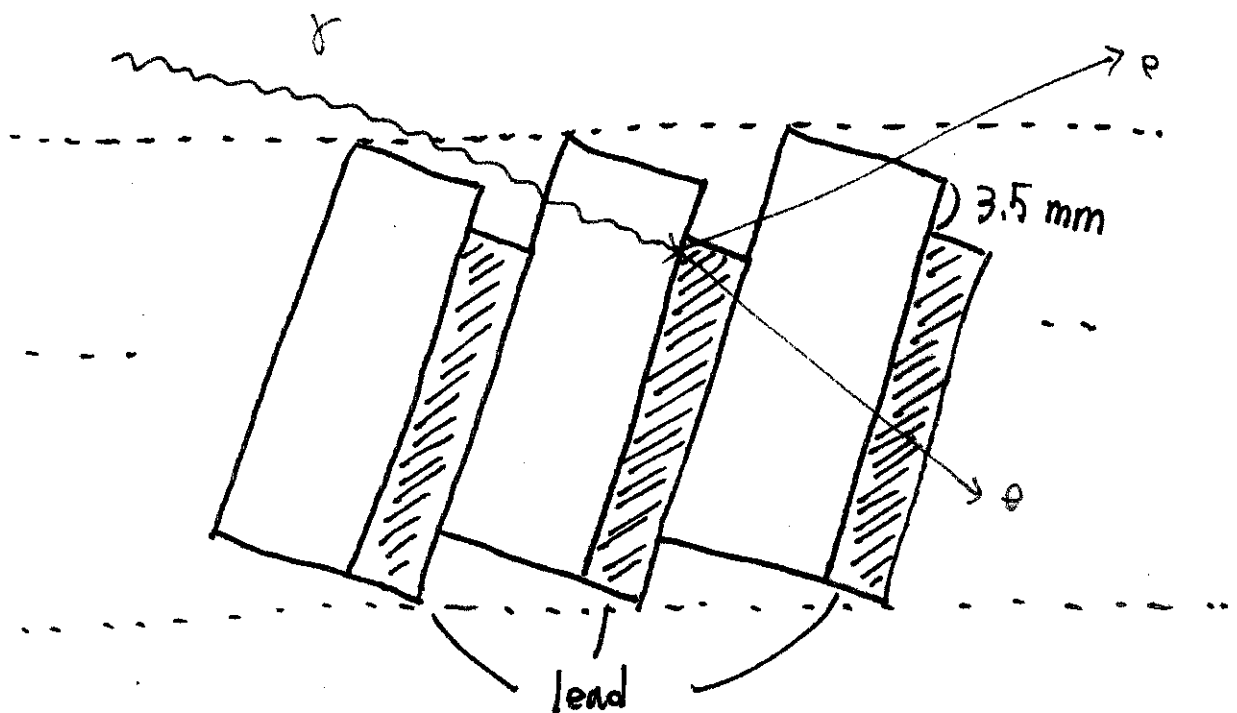
The inefficiency increases under 40° .

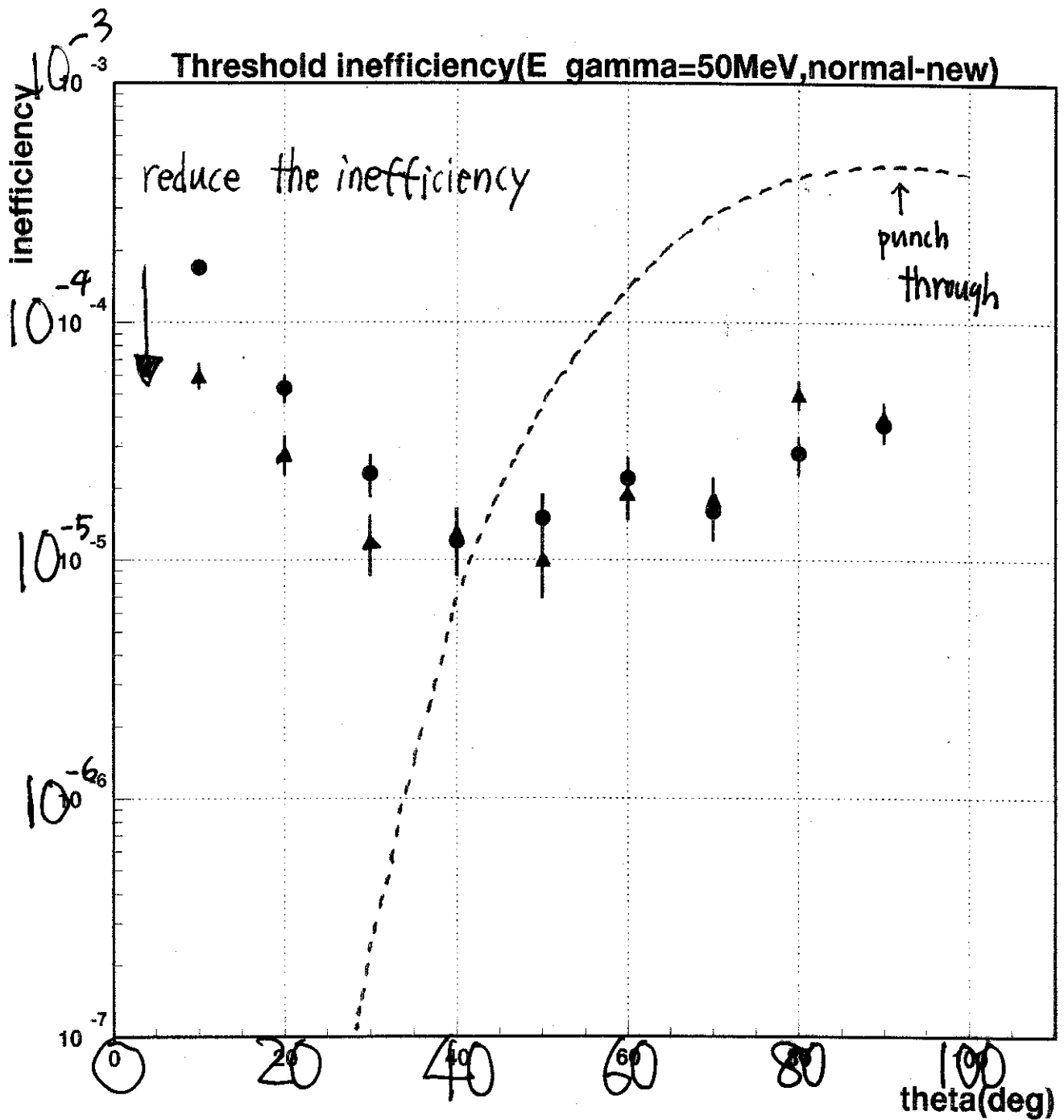
I considered its cause is this electron (positron) can not deposit energy enough.



So, I change the geometry to reduce this event.

in this case, this electron (positron) can deposit energy enough.





Conclusion

① The number of photons ($K_L \rightarrow \pi^0 \pi^0$)
the small incident angle



the large incident angle

② The cause of the inefficiency

punch through : $\theta > 40^\circ$

sampling effect : $\theta < 40^\circ$

③ The reduction of the inefficiency (at $\theta < 40^\circ$)

(i) the backsplash event

place a scintillator sheet

in the front of the lead sheet.

(ii) the event that the electron goes through
the lead long length.

cross the detector (sheets) and the beam ax

(iii) to get more effect

enough deposit energy.

